

**Notice of References Cited**

Application/Control No.

09/307,485

Patent(s) Under

Examination

CHIN, STEPHEN

Examiner

Jeffrey C Pwu

Art Unit

2164

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
	A	US-6119106-A	12-2000	Mersky et al.	705	40
	B	US-6070798-A	06-2000	Nethery	235	462.01
	C	US-5220501-A	06-1993	Lawlor et al.	364	408
	D	US-6012045-A	01-2000	Barzilai et al.	705	37
	E	US-6058379-A	05-2000	Odom et al.	705	37
	F	US-6073117-A	06-2000	Oyanagi et al.	705	38
	G	US-6167386-A	12-2000	Brown	705	37
	H	US-6058417-A	05-2000	Hess et al.	709	219
	I	US-6044363-A	03-2000	mori et al.	705	37
	J	US- -				
	K	US- -				
	L	US- -				
	M	US- -				

**FOREIGN PATENT DOCUMENTS**

*		Document Number	Date	Country	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY				
	N	WO-00/34899-A1	06-2000	PCT	Handler	G06F	17/30
	O	- -					
	P	- -					
	Q	- -					
	R	- -					
	S	- -					
	T	- -					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.